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•	Meets or Exceeds the Requirements of IOS 8802.3:1989 and ANSI/IEEE Std 802.3-1988	DW OR NT PACKAGE (TOP VIEW)
•	Interdevice Loopback Paths for System Testing	TXI1 1 24 TXO1 TXEN1 2 23 TXO1
•	Squelch Function Implemented on the Receiver Inputs	$\begin{array}{c c} \hline LOOP1 \\ \hline 3 \\ \hline 22 \\ \hline V_{CC} \\ \hline RXI1 \\ \hline \end{array}$
•	Drives a Balanced 78- $\Omega$ Load	RXEN1 🛛 5 20 🗍 RXI1
•	Transformer Coupling Not Required in System	RXO1 [] 6 19 ]] GND RXO2 [] 7 18 ]] GND
•	Power-Up/Power-Down Protection (Glitch Free)	RXEN2[] 8 17[] RXI2 GND[] 9 16[] RXI2 LOOP2[] 10 15[] V <sub>CC</sub>
•	Isolated Ground Pins for Reduced Noise Coupling	LOOP2[ 10 15 ] V <sub>CC</sub> TXEN2[ 11 14 ] TXO2 TXI2[ 12 13 ] TXO2
•	Fault-Condition Protection Built Into the Device	

- Driver Inputs Are Level-Shifted ECL Compatible
- Package Options Include Plastic Small-Outline (DW) Package and Standard Plastic (NT) DIP

#### description

The SN75ALS085 is a high-speed, advanced low-power Schottky, dual-channel driver/receiver device designed for use in the AUI of ANSI/IEEE Std 802.3-1988. The two drivers on the device drive a  $78-\Omega$  balanced, terminated twisted-pair transmission line up to a maximum length of 50 meters. In the off (idle) state, the drivers maintain minimal differential output voltage on the twisted-pair line and, at the same time, remain within the required output common-mode range.

With the driver enable (TXEN) high, upon receiving the first falling edge into the driver input, the differential outputs rise to full-amplitude output levels within 25 ns. The output amplitude is maintained for the remainder of the packet. After the last positive packet edge is transmitted into the driver, the driver maintains a minimum of 70% full differential output for a minimum of 200 ns, then decays to a minimum level for the reset (idle) condition within 8  $\mu$ s. Disabling the driver by taking the driver enable low also forces the output into the idle condition after the normal 8- $\mu$ s timeout. While operating, the drivers are able to withstand a set of fault conditions and not suffer damage due to the faults being applied. The drivers power up in the idle state to ensure that no activity is placed on the twisted-pair cable, which could be interpreted as network traffic.

The line receiver squelch function interfaces to a differential twisted-pair line terminated external to the device. The receiver squelch circuit allows differential receive signals to pass through, as long as the input amplitude and pulse duration are greater than the minimum squelch threshold. This ensures a good signal-to-noise ratio while the data path is active and prevents system noise from causing false data transitions during line shutdown and line-idle conditions. The receiver outputs (RXO) default to a high level and the receiver-enable (RXEN) outputs default to a low level while the squelch function is blocking the data path through the receiver (idle). The line receiver squelch becomes active within 50 ns when the input squelch threshold is exceeded. RXEN is driven high when the squelch circuit allows data to pass through the receiver. The receiver squelch circuit also can withstand a set of fault conditions while operating, without causing permanent damage to the device.



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#### description (continued)

The purpose of the loop functions is to provide a means by which system data-path verification can be done to isolate faulty interfaces and assist in network diagnosis. The LOOP pins are TTL compatible and must be held high for normal operation. When LOOP1 is taken low, the output of driver 1 (TXO1) immediately goes into the idle state. Also, the input to receiver 1 is ignored, and a path from a transmit input (TXI1) to RXO1 is established. When LOOP1 is taken back high, driver 1 and receiver 1 revert back to their normal operation. When LOOP2 is taken low, a similar data path is established between TXI1 and RXO2. TXEN1 must be high for the loop functions to operate, and TXEN1 can be used to gate the loop function if desired. During loop operation, the respective RXEN reflects the status of TXEN1.

The SN75ALS085 is characterized for operation from 0°C to 70°C.

	PACKAGED	DEVICES							
TA	PLASTIC SMALL OUTLINE (DW)	PLASTIC DIP (NT)							
0°C to 70°C	SN75ALS085DW	SN75ALS085NT							

AVAILABLE OPTIONS

The DW package is available taped and reeled. Add the suffix R to device type (e.g., SN75ALS085DWR).

#### **Function Tables**

#### RECEIVER ( $\overline{LOOP} = H$ )

RXI		PREVIOUS	OUTPUTS		
KAI	RXEN	RXEN	RXO		
$V_{ID}$ = 1315 mV to -175 mV,	t <sub>W</sub> < 25 ns	L	L	Н	
$V_{ID} = -275 \text{ mV} \text{ to} -1315 \text{ mV}$	t <sub>W</sub> > 50 ns	Х	н	L	
$V_{ID}$ = 318 mV to 1315 mV,	t <sub>W</sub> < 142 ns	н	н	Н	
V <sub>ID</sub> = 318 mV to 1315 mV,	t <sub>w</sub> > 187 ns	Х	L	Н	

H = high level, L = low level, X = don't care

ТХІ	TXEN	PREVIOUS TXO	OUTPUT TXO
L	L	Idle	Idle
н	L	Idle	Idle
$\downarrow$	н	Idle	L
L	н	Active	L
H < 260 μs	н	Active	н
H > 8 μs	н	Active	Idle
L	L > 8 µs	Active	Idle
H < 260 ns	L > 8 μs	Active	Idle
H < 260 ns	L < 260 ns	Active	н
H > 8 μs	L < 260 ns	Active	Idle
L	L < 260 ns	Active	L

#### DRIVER ( $\overline{LOOP} = H$ )

 $H = V_I \ge V_T \text{ max}, L = V_I \le V_T \text{ min}$ 



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					LOOP					
		INP	UTS			OUTPUTS				
LOOP1	LOOP2	TXI1	TXEN1	RXI1	RXI2	RXO1	RXO2	RXEN1	RXEN2	TXO1
L	L	L	Н	Х	Х	L	L	Н	Н	Idle
L	L	Н	Н	Х	Х	Н	Н	Н	Н	Idle
L	L	Х	L	Х	Х	Н	Н	L	L	Idle
L	Н	L	Н	Х	Normal	L	Normal	Н	Normal	Idle
L	Н	Н	Н	Х	Normal	Н	Normal	Н	Normal	Idle
L	Н	Х	L	Х	Normal	Н	Normal	L	Normal	Idle
Н	L	L	Н	Normal	Х	Normal	L	Normal	Н	Idle
н	L	Н	н	Normal	Х	Normal	н	Normal	Н	Idle
н	L	Х	L	Normal	Х	Normal	Н	Normal	L	Idle
Н	Н	Normal	Normal	Normal	Normal	Normal	Normal	Normal	Normal	Normal

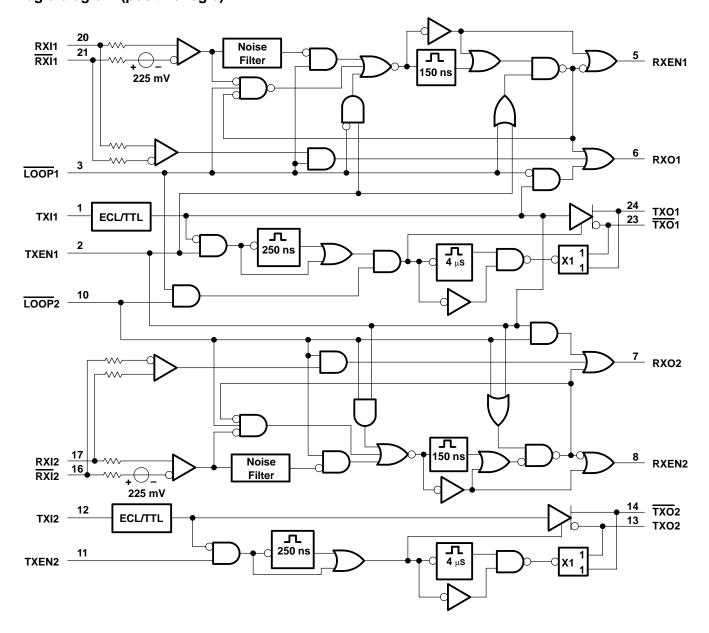
Function Tables (continued)

H = high level, L = low level, X = don't care



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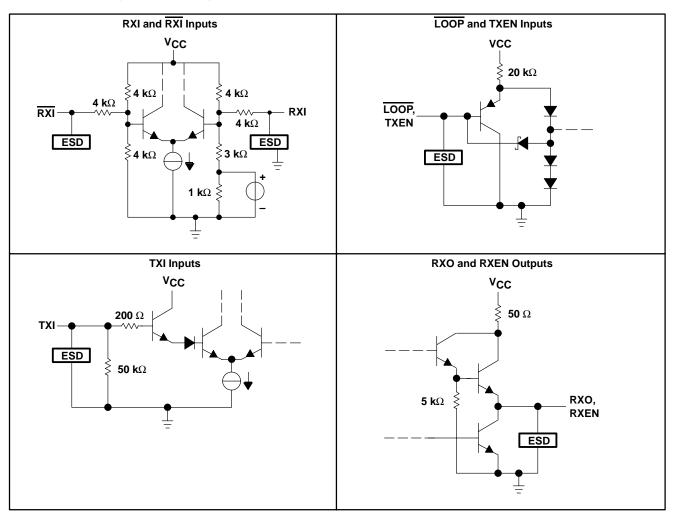
## logic diagram (positive logic)





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### schematics of inputs and outputs





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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC</sub> (see Note 1) TXI and LOOP input voltage, V <sub>I</sub>	
TXO and TXO output voltage, $V_{O}$	
RXI and RXI input voltage, VI	
RXO and RXEN output voltage, V <sub>O</sub>	5.5 V
Package thermal impedance, $\theta_{JA}$ (see Notes 2 and 3): DW package	46°C/W
(see Notes 2 and 4): NT package	67°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T <sub>stg</sub>	–65 to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. Voltage values are with respect to network ground terminal.

- 2. Maximum power dissipation is a function of T<sub>J</sub>(max),  $\theta_{JA}$ , and T<sub>A</sub>. The maximum allowable power dissipation at any allowable ambient temperature is P<sub>D</sub> = (T<sub>J</sub>(max) T<sub>A</sub>)/ $\theta_{JA}$ . Operating at the absolute maximum T<sub>J</sub> of 150°C can affect reliability.
- 3. The package thermal impedance is calculated in accordance with JESD 51-7.
- 4. The package thermal impedance is calculated in accordance with JESD 51-3.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.75	5	5.25	V
VIC	Common-mode voltage at RXI inputs	1		4.2	V
$V_{ID}$	Differential voltage between RXI inputs	±318		±1315	mV
VIH	High-level input voltage, LOOP and TXEN	2			V
VIL	Low-level input voltage, LOOP and TXEN			0.8	V
IOH	High-level output current, RXO and RXEN			- 0.4	mA
IOL	Low-level output voltage, RXO and RXEN			16	mA
t <sub>su1</sub>	Setup time, driver mode, TXEN high before TXI $\downarrow$ (see Figure 7)	10			ns
t <sub>su2</sub>	Setup time, loop mode, $\overline{\text{LOOP}}$ low before TXEN $\uparrow$ (see Figure 9)	15			ns
t <sub>su3</sub>	Setup time, loop mode, TXEN high before TXI $\downarrow$ (see Figure 9)	10			ns
<sup>t</sup> h1	Hold time, loop mode, TXEN high after TXI↑ (see Figure 8)	10			ns
t <sub>h2</sub>	Hold time, loop mode, $\overline{\text{LOOP}}$ low after TXEN $\downarrow$ (see Figure 8)	15			ns
Тд	Operating free-air temperature	0		70	°C



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# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEST C	ONDITIONS	MIN	MAX	UNIT	
VIK	Clamp voltage at all inputs		lı = –18 mA			-1.5	V	
				V <sub>CC</sub> = 4.75 V	3.202	3.752		
			$T_A = 0^{\circ}C$	V <sub>CC</sub> = 5 V	3.389	3.998		
			V <sub>CC</sub> = 5.25 V	3.577	4.244			
.,				V <sub>CC</sub> = 4.75 V	3.213	3.797		
V(TO)	Driver input (TXI) threshold voltage		T <sub>A</sub> = 25°C	V <sub>CC</sub> = 5 V	3.400	4.043	V	
· · /					3.588	4.289		
				V <sub>CC</sub> = 4.75 V	3.239	3.849		
			T <sub>A</sub> = 70°C	V <sub>CC</sub> = 5 V	3.426	4.095		
			V <sub>CC</sub> = 5.25 V	3.614	4.341			
	Receiver differential input threshold voltage			-		-275	mV	
		Idle	TXEN at 0.8 V, LOOP2 at 2 V,	LOOP1 at 2 V, See Figure 1	1	4.2		
Voc	Driver output (TXO) common-mode voltage	Active	TXEN at 2 V, LOOP2 at 2 V, See Figure 1	LOOP1 at 2 V, TXI at 3.2 V,	1	4.2	V	
		Active	TXEN at 2 V, LOOP2 at 2 V, See Figure 1	LOOP1 at 2 V, TXI at 4.4 V,	1	4.2		
	Driver output (TXO) differential voltage		Idle	TXEN at 0.8 V, LOOP2 at 2 V,	LOOP1 at 2 V, See Figure 1		±40	
Vod		Active	TXEN at 2 V, LOOP2 at 2 V, See Figure 1	LOOP1 at 2 V, TXI at 3.2 V,	- 600	1315	mV	
		Active	TXEN at 2 V, LOOP2 at 2 V, See Figure 1	LOOP1 at 2 V, TXI at 4.4 V,	600	1315		
Vон	High-level output voltage	RXO, RXEN	I <sub>OH</sub> = -0.4 mA		2.4		V	
VOL	Low-level output voltage	RXO, RXEN	I <sub>OL</sub> = 16 mA			0.5	V	
		TXEN, LOOP	V <sub>I</sub> = 2 V			20		
IH	High-level input current	ТХІ	VI = 4.5 V			400	μA	
		RXI, RXI	$V_{ID} = -0.5 V,$	$V_{IC} = 1 V \text{ to } 4.2 V$		1000		
		TXEN, LOOP	V <sub>I</sub> = 0.8 V			-200		
			V <sub>I</sub> = 3.1 V			100		
IL	Low-level input current	ТХІ	V <sub>I</sub> = 0.3 V		4	10	μA	
		RXI, RXI	V <sub>ID</sub> = 0.5 V,	$V_{IC}$ = 1 V to 4.2 V		1000		
OD	Driver differential output current	Idle	TXEN at 0.8 V, LOOP2 at 2 V,	LOOP1 at 2 V, See Figure 2		±4	mA	
OS	Short-circuit output current <sup>†</sup>	RXO, RXEN	V <sub>O</sub> at 0 V, RXI at 2 V	RXI at 3 V,	- 40	- 150	mA	
сс	Supply current		LOOP2 at 2 V, TXI at 4.5 V,	TXEN at 2 V, Outputs open		225	mA	

<sup>†</sup> Not more than one output should be shorted at a time, and the duration of the test should not exceed 1 second.



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# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

PARAMETER		TEST CO	NDITIONS	MIN	MAX	UNIT
	TXO shorted to TXO,	Current measu	red in short		150	
	TXO at 0 V,	TXO is open,	Current measured at TXO		150	
	TXO is open,	TXO at 0,	Current measured at TXO		150	
Driver fault condition current‡	TXO at 0 V,	TXO at 0 V,	Current measured at TXO and $\overline{TXO}$		150	mA
	TXO at 16 V,	TXO is open,	Current measured at TXO		150	
	TXO is open,	TXO at 16 V,	Current measured at TXO		150	
	TXO at 16 V,	TXO at 16 V,	Current measured at TXO and TXO		150	
	TXO shorted to TXO, Current measurement   TXO at 0 V, TXO is open,   TXO is open, TXO at 0,   TXO at 0 V, TXO at 0,   TXO at 16 V, TXO is open,   TXO is open, TXO at 16 V,   TXO at 16 V, TXO at 16 V,   TXO at 16 V, TXO at 16 V,   RXI shorted to RXI, Current measurement   RXI at 0 V, RXI is open,   RXI at 0 V, RXI at 0 V,	Current measu	red in short		10	
	RXI at 0 V,	RXI is open,	Current measured at RXI		3	
	RXI is open,	RXI at 0 V,	Current measured at RXI		3	
Receiver fault condition current‡	RXI at 0 V,	RXI at 0 V,	Current measured at RXI and RXI		3	mA
	RXI at 16 V,	RXI at open,	Current measured at RXI		10	
	RXI at open,	RXI at 16 V,	Current measured at RXI		10	
	RXI at 16 V,	RXI at 16 V,	Current measured at RXI and RXI		10	

<sup>‡</sup> Fault conditions should be measured on only one channel at a time.

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

#### driver

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CC	ONDITIONS	MIN	МАХ	UNIT
<sup>t</sup> PLH	Propagation delay time, low-to-high level output	ТХІ	TXO, TXO	TXEN at 2 V,	See Figure 3		15	ns
<sup>t</sup> PHL	Propagation delay time, high-to-low level output	ТХІ	τχο, <del>τχο</del>	TXEN at 2 V,	See Figure 3		15	ns
<sup>t</sup> PIL	Propagation delay time, idle-to-low level output	ТХІ	TXO, TXO	TXEN at 2 V,	See Figure 4		25	ns
<sup>t</sup> PIL	Propagation delay time, idle-to-low level output	TXEN	TXO, TXO	TXI at 3.2 V,	See Figure 5		25	ns
tw	Output pulse duration, from low-to-high level to 70% output level		TXO, TXO	TXEN at 2 V,	See Figure 6	260	8000	ns
V <sub>OD(U)</sub>	Driver output differential undershoot voltage	ТХІ	TXO, TXO	TXEN at 2 V,	See Figure 6		-100	mV
t <sub>sk</sub>	Driver caused signal skew <sup>t</sup> PLH <sup>– t</sup> PHL	ТХІ	TXO, TXO	TXEN at 2 V,	See Figure 3		±3	ns
t <sub>r</sub>	Rise time, TXO, TXO			TXEN at 2 V,	See Figure 3	1	5	ns
t <sub>f</sub>	Fall time, TXO, TXO			TXEN at 2 V,	See Figure 3	1	5	ns



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receiv	ver						
	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	МАХ	UNIT
<sup>t</sup> PLH	Propagation delay time, low-to-high level output	RXI, RXI	RXO	$V_{IC} = 1 V$ to 4.2 V, See Figure 10		15	ns
<sup>t</sup> PHL	Propagation delay time, high-to-low level output	RXI, RXI	RXO	$V_{IC}$ = 1 V to 4.2 V, See Figure 10		15	ns
<sup>t</sup> PLH	Start-up delay time, low-to-high level output	RXI, RXI	RXEN	$V_{IC}$ = 1 V to 4.2 V, $V_{ID}$ = -500 mV, See Figure 12		55	ns
<sup>t</sup> PHL	Shutdown delay time, high-to-low level output	RXI, RXI	RXEN	$V_{IC}$ = 1 V to 4.2 V, $V_{ID}$ = 500 mV, See Figure 12	142	181	ns
<sup>t</sup> sk	Receiver caused signal skew (tpLH – tpHL)	RXI, RXI	RXO	$V_{IC}$ = 1 V to 4.2 V, $V_{ID}$ = 500 mV, See Figure 10		±3	ns
tw	Pulse duration at $\overline{RXI}$ and $RXI$ (to not activate squelch)			$V_{IC} = 1 V$ to 4.2 V, $V_{ID} = -175 \text{ mV}$ , See Figure 11	25		ns
tw	Pulse duration at $\overline{RXI}$ and $RXI$ (to activate squelch)			$V_{IC} = 1 V$ to 4.2 V, $V_{ID} = -275 mV$ , See Figure 11		50	ns
t <sub>r1</sub>	Rise time, RXO			$V_{IC}$ = 1 V to 4.2 V, $V_{ID}$ = ±500 mV, See Figure 10	1	8	ns
t <sub>r2</sub>	Rise time, RXEN			$V_{IC}$ = 1 V to 4.2 V, $V_{ID}$ = $\pm500$ mV, See Figure 12	1	8	ns
<sup>t</sup> f1	Fall time, RXO			$V_{IC}$ = 1 V to 4.2 V, $V_{ID}$ = ±500 mV, See Figure 10	1	8	ns
<sup>t</sup> f2	Fall time, RXEN			$V_{IC}$ = 2.5 V, $V_{ID}$ = ±500 V, See Figure 12	1	8	ns
t <sub>v</sub>	RXO valid after RXEN high			See Figure 10	-10	15	ns

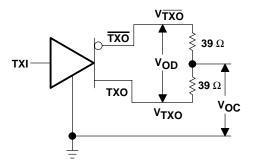
#### loop

PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low-to-high level output	ТХІ	RXO	LOOP at 0.8 V, TXEN at 2 V, See Figure 13	30	ns
<sup>t</sup> PHL	Propagation delay time, high-to-low level output	ТХІ	RXO	LOOP at 0.8 V, TXEN at 2 V, See Figure 13	30	ns
<sup>t</sup> PLH	Propagation delay time, low-to-high level output	TXEN	RXEN	LOOP at 0.8 V, See Figure 14	50	ns
<sup>t</sup> PHL	Propagation delay time, high-to-low level output	TXEN	RXEN	LOOP at 0.8 V, See Figure 14	50	ns



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#### PARAMETER MEASUREMENT INFORMATION





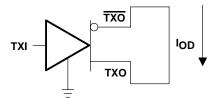
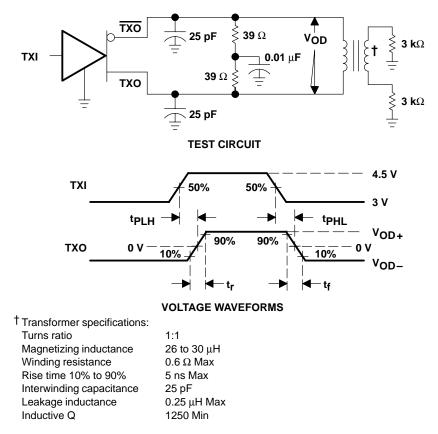
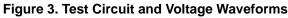


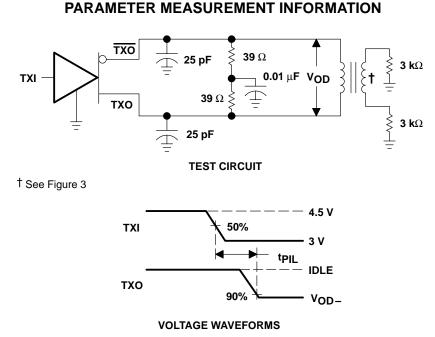
Figure 2. Driver Test Circuit





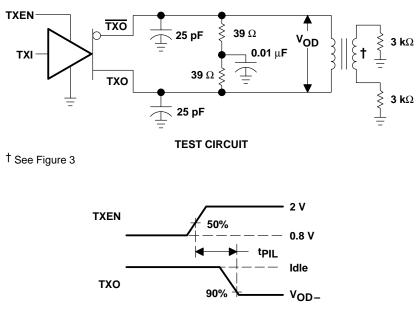


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NOTE A: Input  $t_r \le 5$  ns;  $t_f \le 5$  ns

#### Figure 4. Test Circuit and Voltage Waveforms

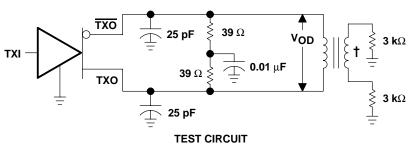


**VOLTAGE WAVEFORMS** 

Figure 5. Test Circuit and Voltage Waveforms



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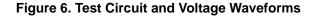


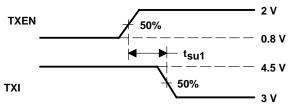
#### PARAMETER MEASUREMENT INFORMATION

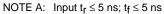




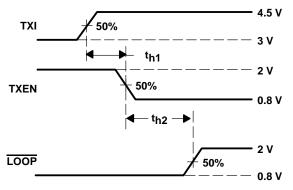
**VOLTAGE WAVEFORMS** 











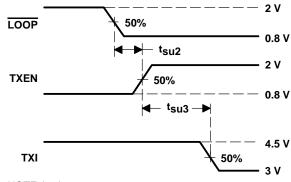
NOTE A: Input  $t_{f} \le 5$  ns;  $t_{f} \le 5$  ns

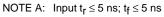
Figure 8



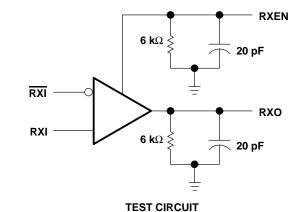
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### PARAMETER MEASUREMENT INFORMATION

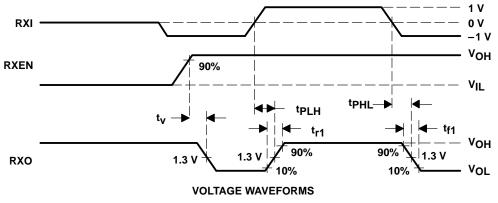




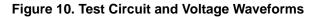






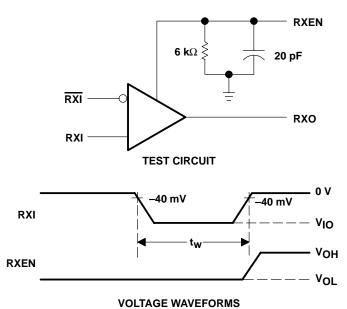


NOTE A: Input  $t_f \le 5$  ns;  $t_f \le 5$  ns



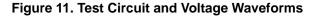


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PARAMETER MEASUREMENT INFORMATION

NOTE A: Input  $t_{f} \le 5$  ns;  $t_{f} \le 5$  ns



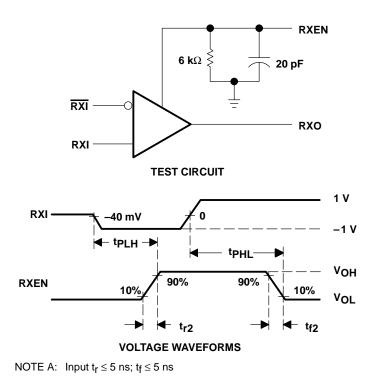
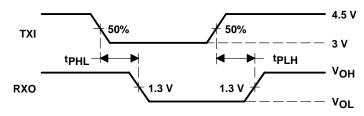


Figure 12. Test Circuit and Voltage Waveforms



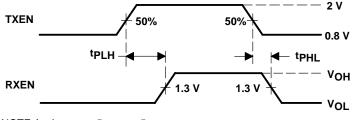
SLLS054D - APRIL 1989 - REVISED OCTOBER 2001

## PARAMETER MEASUREMENT INFORMATION



NOTE A: Input  $t_f \le 5$  ns;  $t_f \le 5$  ns





NOTE A: Input  $t_f \le 5$  ns;  $t_f \le 5$  ns

Figure 14





10-Dec-2020

### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN75ALS085DW	NRND	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	75ALS085	

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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5-Jan-2022

### TUBE



#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
SN75ALS085DW	DW	SOIC	24	25	506.98	12.7	4826	6.6

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AD.



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